Docket Number: 081468-0308636

Client Reference: P-1519.010-US



PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re the Application of

ALBERT JAN HENDRIK KLOMP, et al.

Group Art Unit: 2851

Application No.: 10/797,725

Examiner: Kevin C. Gutierrez

Filed: March 11, 2004

Confirmation No.: 4128

For: LITHOGRAPHIC PROJECTION ASSEMBLY, LOAD LOCK AND METHOD FOR

TRANSFERRING OBJECTS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR 1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. One copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom. Applicant respectfully requests the Examiner return an initialed copy of the enclosed Form PTO-1449 to Applicant with the next Office communication to indicate that the references have been considered, per MPEP § 609.

This Information Disclosure Statement is being filed before the mailing date of a first Office Action after the filing of a request for continued examination under 37 C.F.R. §1.114. No certification or fee is required.

The references were cited in counterpart Japanese application. An English language version of the Japanese office action is attached for the Examiner's information. A Singapore office action is also attached for the Examiner's information. All of the references cited in the Singapore office action were previously submitted in an Information Disclosure Statement.

English-language Abstracts of the references are attached hereto.

Respectfully Submitted,

PILLSBURY WINTHROP SHAW PITTMAN LLP

Emily T. Bell

Registration Number 47418 Customer Number: 00909

Date: June 20, 2007

Telephone: (703) 770-7900 Facsimile: (703) 770-7901

P.O. Box 10500 McLean, VA 22102

All	. خمنوند	٠- الم													
Patent and Trademark Office July 2 0 1007 Patent and Trademark Office Patent and Tradema	FORM PTO-	449	(modified)		A	318	4	Atty.	M#		Client	Ref.			
NFORMATION DISCLOSURE STATEMENT State St					Dkt. No.										
Date June 20, 2007 Page 1 of 1 Examiner K GUIDENTS English Rame K R R R R R R R R R					()	UN 2	(بير 2007 (- 1			
Appln. No.: 10/797,725	, atom a				13		Ę)								
Appln. No.: 10/797,725	081468 0308636										P-15	P-1519.010-US			
Applin. No.: 10/797,725 Filing Date: March 11, 2004 Examiner: K. GUTIERREZ Group Art Unit: 2851	INFORMATION DISCLOSURE STATEMENT Applicant: KLOMP et al.														
Filing Date: March 11, 2004 Examiner: K. GUTIERREZ Group Art Unit: 2851	BY APPLI	CAN	IT						******						
Date June 20, 2007 Page 1 of								Appln. N	lo.: 10/797,72	5					
U.S. PATENT DOCUMENTS															
Examiner's Document Date MM/YYYY Name of First Inventor)	Date: June 2	20, 2	.007	Page	_ 1	of	1	Examine	er: K. GUTIERI	REZ Gro	up Art Ui	<u>nit: 2</u>	2851		
Number	U.S. PATEN	IT D	OCUMENTS]				1.		Г		
AR					ł				Class	l l	_	_			
BR	Initials*		Number	MM/YYYY		(Family Name of First Inve		nventor)	-	Class	Class (ii app		1(e)		
CR	ļ	-			ļ										
DR		-								 			<u> </u>		
FR					ļ		ļ				-		-		
FR		-			 		-			_					
GR		\vdash			-										
HR					-		<u> </u>								
IR		_			ļ						<u> </u>				
JR				1											
KR		-					<u> </u>								
LR		-													
MR															
NR							· · · · · · · · · · · · · · · · · · ·								
Document Number						•									
Document Number	FOREIGN F	PATE	NT DOCUMENT	s						, , , , , , , , , , , , , , , , , , , 	English			n n	
Number			T		Count		try	Inventor Na	me		Abstract				
OR JP 2003-031470 01/2003			Number	mber MM/											
PR JP 2003-023059 01/2003 Japan YAMATSU X X OR JP 2002-033264 01/2002 Japan HATTORI et al. X X RR JP 2001-118904 04/2001 Japan ETO X X X SR JP 2001-015432 01/2001 Japan FUJIOKA et al. X X TR UR UR VR OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.) WR Japanese Office Action issued for Japanese Patent Application No. 2004-067524, dated April 13, 2007. XR Singapore Office Action issued for Singapore Patent Application No. 200401159-9, dated May 4, 2007. YR ZR AAF BBF Examiner Date Considered: *EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if											Enclosed	No	Enclosed	No	
QR JP 2002-033264 01/2002 Japan HATTORI et al. X X X RR JP 2001-118904 04/2001 Japan ETO X X X SR JP 2001-015432 01/2001 Japan FUJIOKA et al. X X X TR UR UR UR US Japanese Office Action issued for Japanese Patent Application No. 2004-067524, dated April 13, 2007. XR Singapore Office Action issued for Singapore Patent Application No. 200401159-9, dated May 4, 2007. YR ZR AAF BBF Examiner Date Considered: *EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if		OR	JP 2003-031470	01/20	003	Japar	1	SUZUKI et	al.		Х		X		
RR JP 2001-118904 04/2001 Japan ETO X X X SR JP 2001-015432 01/2001 Japan FUJIOKA et al. X X TR UR UR VR OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.) WR Japanese Office Action issued for Japanese Patent Application No. 2004-067524, dated April 13, 2007. XR Singapore Office Action issued for Singapore Patent Application No. 200401159-9, dated May 4, 2007. YR ZR AAF BBF Examiner Date Considered: *EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if		PR	JP 2003-023059	01/2003		Japai	1	YAMATSU			X	$oxed{oxed}$	X	ļ	
SR JP 2001-015432 01/2001 Japan FUJIOKA et al. X X TR UR UR OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.) WR Japanese Office Action issued for Japanese Patent Application No. 2004-067524, dated April 13, 2007. XR Singapore Office Action issued for Singapore Patent Application No. 200401159-9, dated May 4, 2007. YR ZR AAF BBF Examiner Date Considered: *EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if		QR	JP 2002-033264	01/20	002	Japar	<u> </u>		t al.		 	<u> </u>		 	
TR UR UR OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.) WR Japanese Office Action issued for Japanese Patent Application No. 2004-067524, dated April 13, 2007. XR Singapore Office Action issued for Singapore Patent Application No. 200401159-9, dated May 4, 2007. YR ZR AAF BBF Examiner Date Considered: *EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if		RR	JP 2001-118904	04/20	001	Japar	n	 				<u> </u>	<u> </u>	┦—	
UR VR OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.) WR Japanese Office Action issued for Japanese Patent Application No. 2004-067524, dated April 13, 2007. XR Singapore Office Action issued for Singapore Patent Application No. 200401159-9, dated May 4, 2007. YR ZR AAF BBF Examiner Date Considered: *EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if		SR	JP 2001-015432	01/20	001	Japar	<u>1</u>	FUJIOKA e	al		X	 	X	╁	
VR OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.) WR Japanese Office Action issued for Japanese Patent Application No. 2004-067524,		\vdash				 					ļ		<u> </u>	+-	
OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.) WR Japanese Office Action issued for Japanese Patent Application No. 2004-067524, X dated April 13, 2007. XR Singapore Office Action issued for Singapore Patent Application No. 200401159-9, dated May 4, 2007. YR ZR AAF BBF Examiner Date Considered: *EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if				<u> </u>		-				\perp	 	\vdash			
WR Japanese Office Action issued for Japanese Patent Application No. 2004-067524, XR Singapore Office Action issued for Singapore Patent Application No. 200401159-9, dated May 4, 2007. YR ZR AAF BBF Examiner Date Considered: *EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if			<u> </u>	<u> </u>		<u></u>					<u> </u>	 	<u> </u>	 	
dated April 13, 2007. XR Singapore Office Action issued for Singapore Patent Application No. 200401159-9, dated May 4, 2007. YR ZR AAF BBF Examiner Date Considered: *EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if	OTHER (Inc											1		4	
dated May 4, 2007. YR ZR AAF BBF Examiner Date Considered: *EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if		<u> </u>	dated April 13, 20	007.						·			X	_	
ZR AAF BBF Examiner Date Considered: *EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if		XR													
BBF Examiner Date Considered: *EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if		YR										<u> </u>		<u> </u>	
Examiner Date Considered: *EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if		ZR								io.	ļ	↓_		 	
Examiner Date Considered: *EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if		AAI	1.40											—	
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if		вв									<u> </u>	<u>L</u>	<u> </u>	<u> </u>	
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if							- 								
			Initial if citation cor	nsidere red In	ed, whe	ether of	r not citation this form with	is in conforma h next commu	ince with MPEP nication to Appli	§ 609. Dra cant.	w line thr	ougl	n citation	IŤ	